



Meeting on Focused Ion Beams in Berlin - FIBiB2017

6th – 7th November 2017 at HZB Wannsee Campus

HZB Helmholtz
Zentrum Berlin

FIBiB2017 is dedicated to focused ion beam based technologies for applications in sample preparation, sample investigation, nanopatterning and imaging. The workshop will gather scientists and technicians for mutual exchange of knowledge and will provide a platform for those interested in FIB technologies without previous expertise.

Topics:

- Fundamentals of ion-matter interaction
- Nanopatterning – approaching the sub-10 nm scale
- Novel approaches in sample preparation and investigation (TEM lamellas, tomography, 3D EBSD, and others)
- Imaging with ions

Important Dates:

Abstract Deadline -> 15th June 2017

Abstract Notification -> 15th July 2017

Registration Deadline -> 31st August 2017

The number of oral contributions and posters is restricted to 15 each. For all participants 45 places will be available. Please register in time!

Invited Presentations:

- **Bert Hecht**, *University Würzburg, Germany*
- **Gregor Hlawacek**, *Helmholtz-Zentrum Dresden Rossendorf, Germany*
- **Matthias Schmidt**, *Helmholtz Centre for Environmental Research, Germany*
- **Peter Sigmund**, *Syddansk Universitet, Denmark*

Social Event:

Conference Dinner at **Schmiede 9** (Kutschstall) in Potsdam

Sponsor:

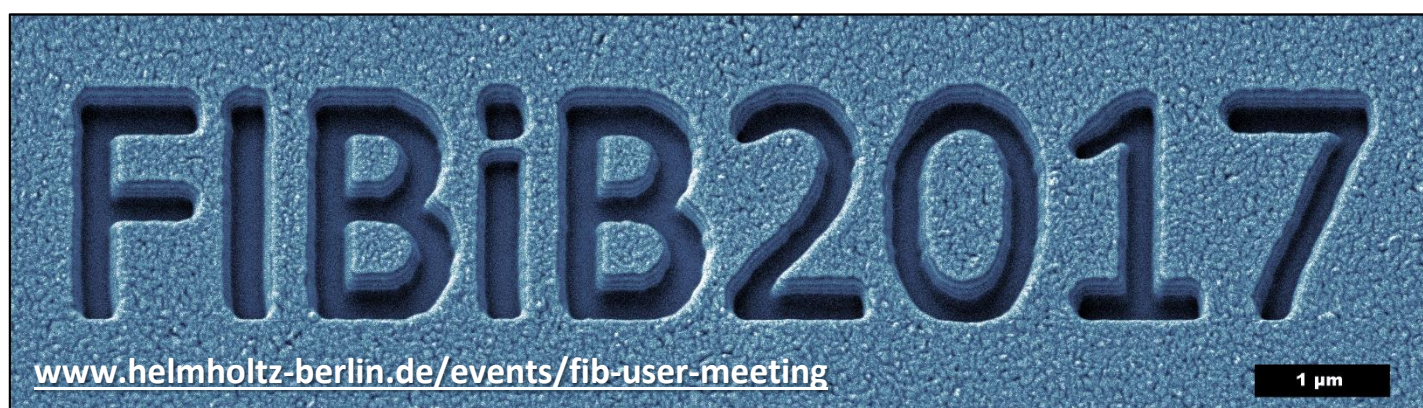


Contact:

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Scientific advisory committee:

Marco Cantoni (École Polytechnique Fédérale de Lausanne); **Gregor Hlawacek** (Helmholtz-Zentrum Dresden-Rossendorf); **Katja Höflich** (Helmholtz-Zentrum Berlin für Materialien und Energie), **Tom Wirtz** (Luxembourg Institute of Science and Technology); **Markus Wollgarten** (Helmholtz-Zentrum Berlin für Materialien und Energie)



www.helmholtz-berlin.de/events/fib-user-meeting

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